

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 025720-00020	SERIAL NO. 10/724,577 Unknown
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Michio MIURA et al.	
		FILING DATE December 1, 2003	GROUP 2817 Unknown

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
BS	AG	2516817	April 30, 1996	Japan	41	22			X
BS	AH	11-55070	February 26, 1999	Japan	9	25	X		
BS	AI	9-208399	August 12, 1997	Japan	33	00			X
	AJ								
	AK								
	AL								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

BS	AM	SAW Properties of SiO ₂ /128° Y-X LiNbO ₃ Structure Fabricated by Magnetron Sputtering Technique Kazuhiki YAMANOUCHI, Member IEEE, and Satoshi HAYAMA, <i>IEEE Transactions On Sonics And Ultrasonics</i> , Vol. SU-31, No. 1, January 1984, pp. 51-57.
BS	AN	Temperature Stable SAW Devices Using Directly Bonded LiTaO ₃ /Glass Substrates H. SATO, K. ONISHI, T. SHIMAMURA, and Y. TOMITA, <i>1998 IEEE Ultrasonics Symposium</i> , Vol. 1, October 1998, pp. 335-338.
BS	AO	Theoretical Analysis of SAW Propagation Characteristics under the Strained Medium and Applications for High Temperature Stable High Coupling SAW Substrates K. YAMANOUCHI, K. KOTANI, H. ODAGAWA, and Y. CHO, <i>1999 IEEE Ultrasonics Symposium</i> , Vol. 1, July 2000, pp. 471-474.

EXAMINER <i>Beulah Summons</i>	DATE CONSIDERED <i>2/15/05</i>
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	